

30nm and 20nm Physical Gate Length CMOS Transistors

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Components Research

Logic Technology Development

Intel Corporation

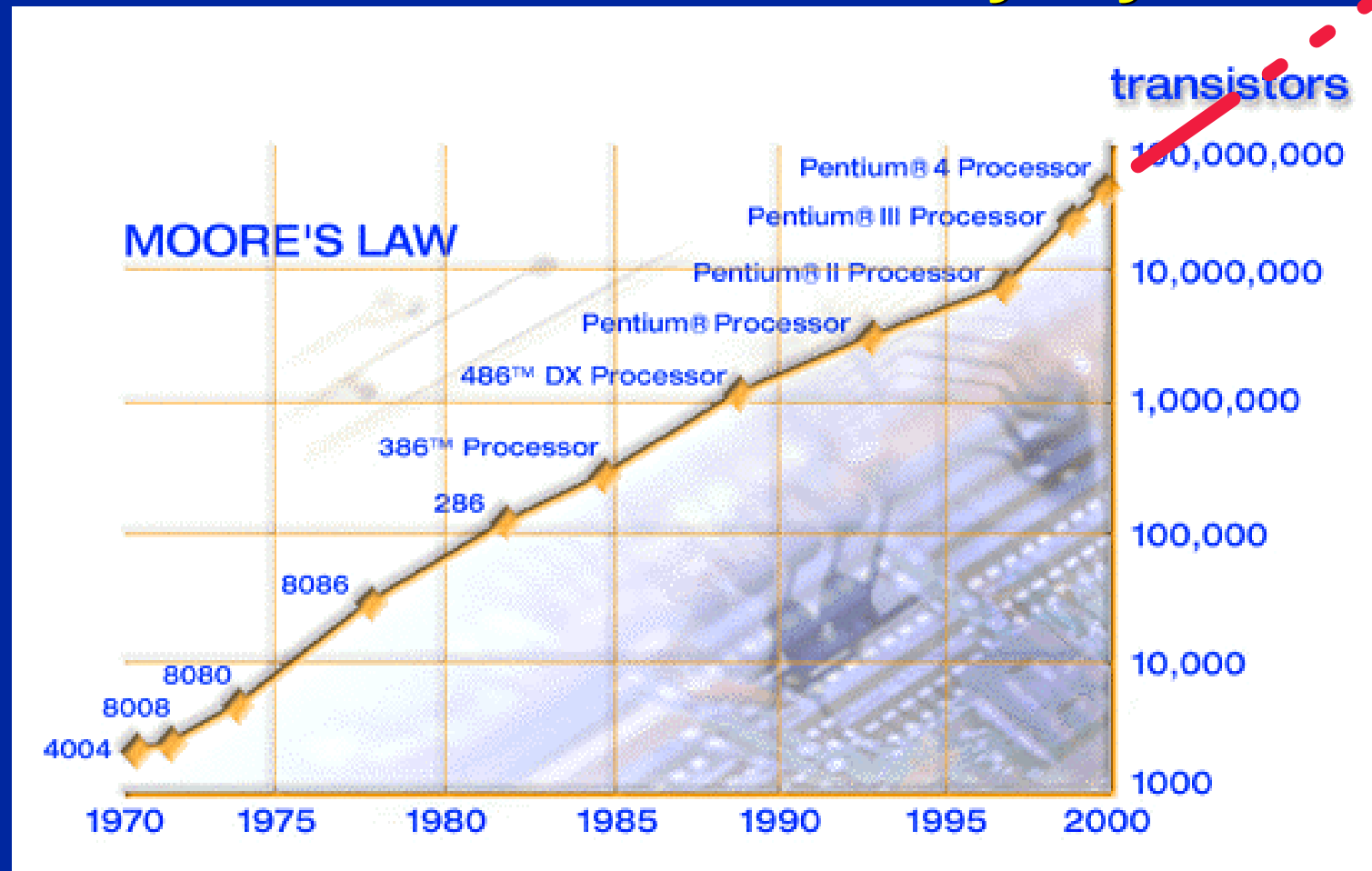
June 10, 2001

Content

- Overview
- Review on 30nm CMOS transistors
- Supply voltage scaling
- 20nm transistor research
- Summary

Moore's Law Continues

Transistors doubles every 2 years

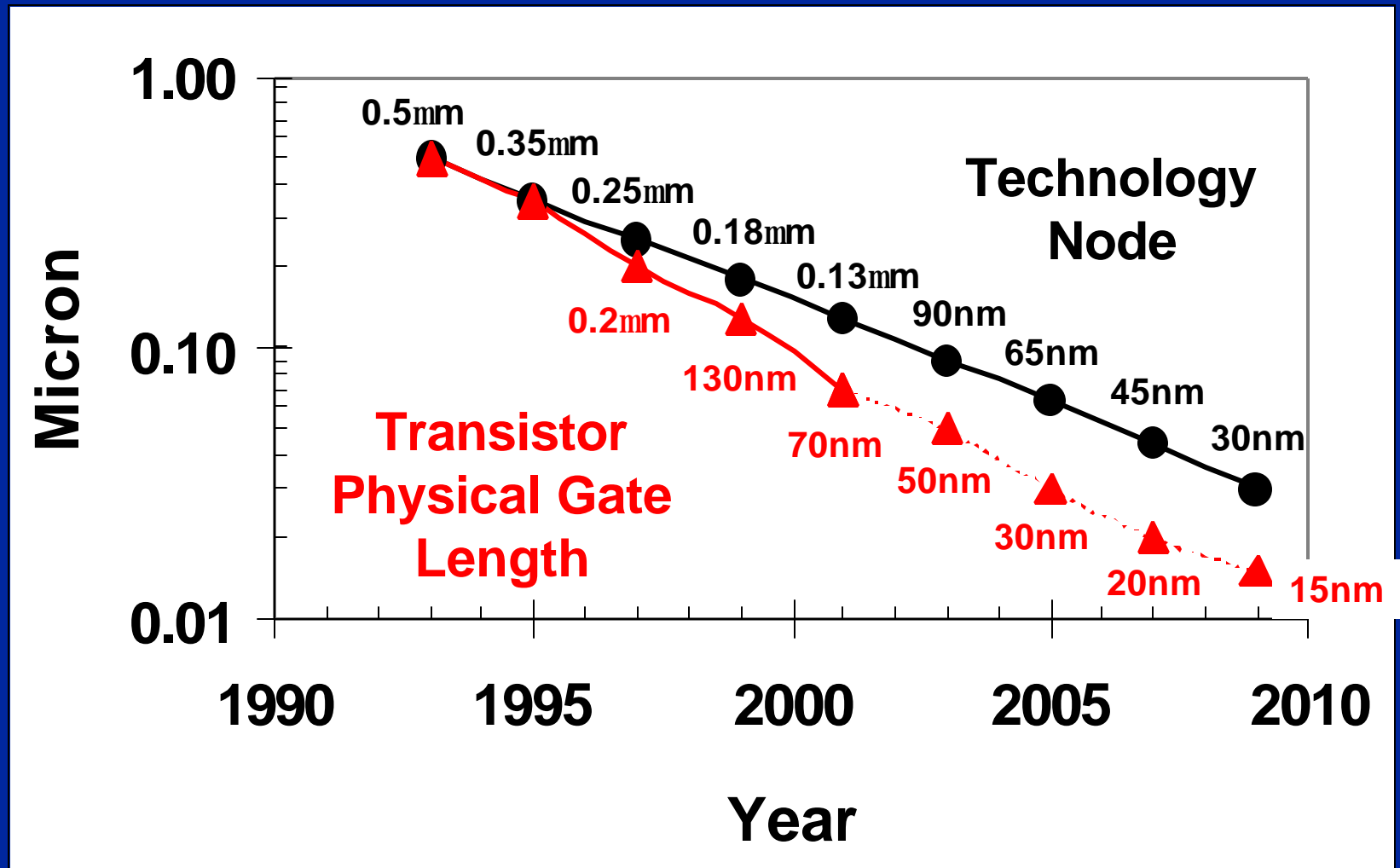


- ~1.0 billion transistors by 2007

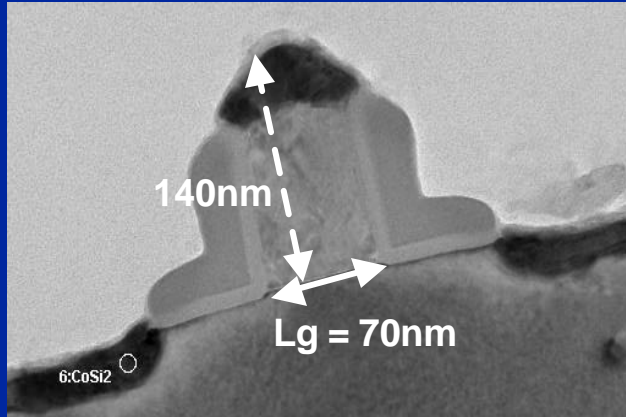
Moore's Law Drives Transistor R&D

- Transistor and supply voltage scaling are key
- 30% shrink in transistor size every 2 years
 - 2X die per wafer
 - 1/2X transistor cost
 - >30% transistor performance improvement
- >15% reduction in supply voltage every generation
 - Low operating voltage allows low power and long battery life

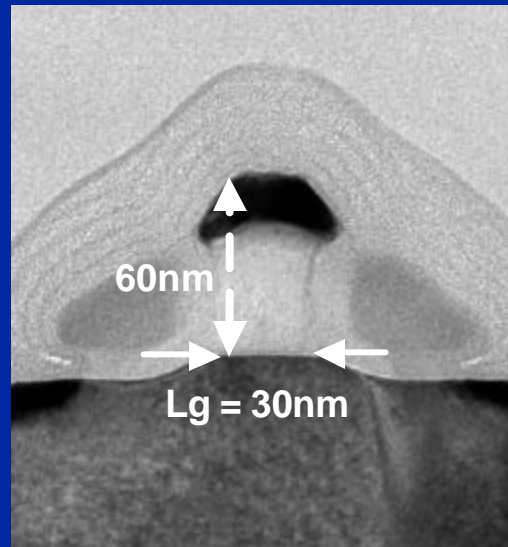
Transistor Physical Gate Length Trend (Lithography generation > L_{GATE})



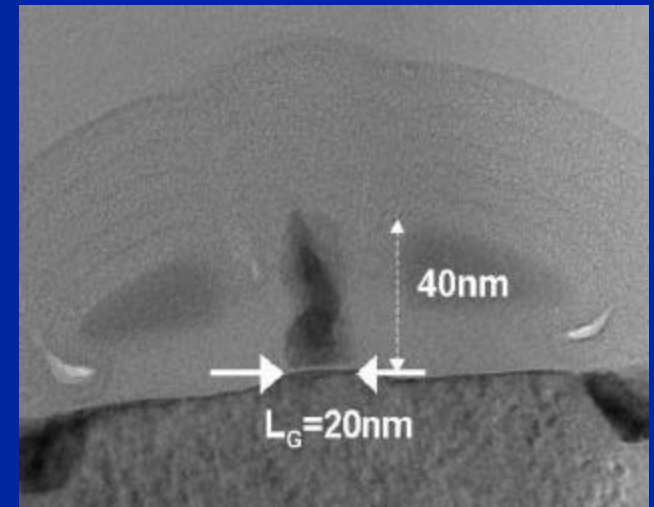
Transistor Scaling Continues



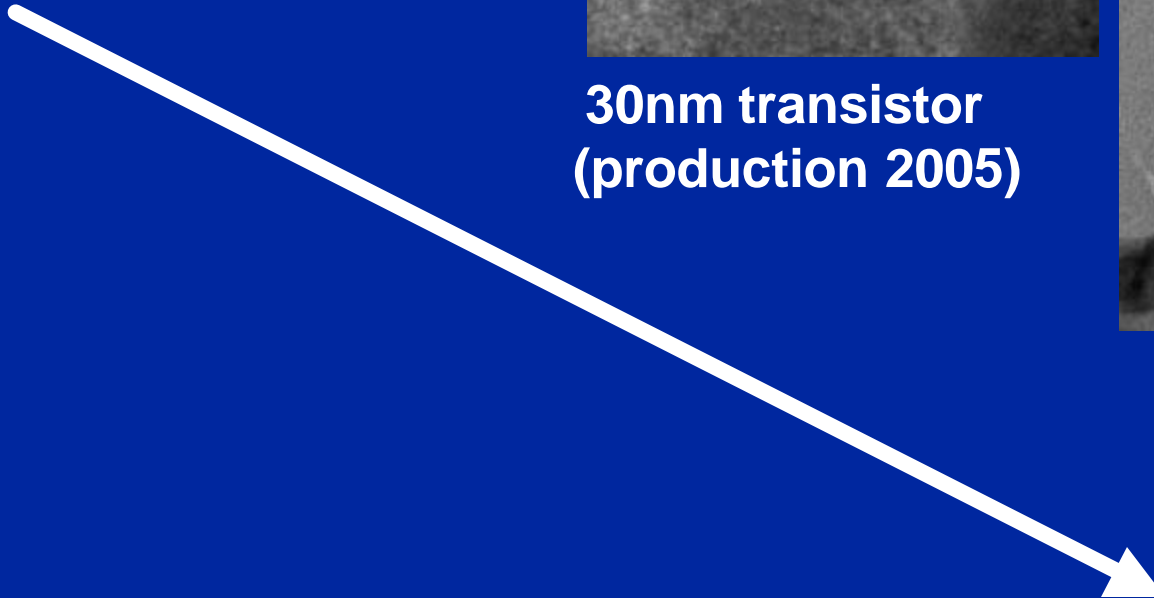
**70nm transistor
(in production)**



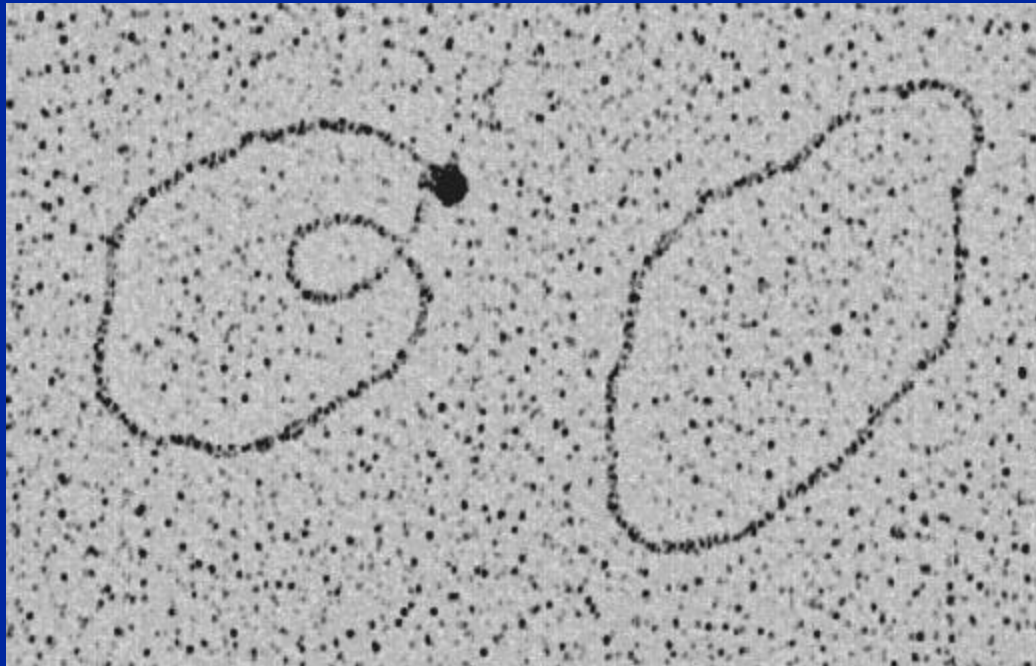
**30nm transistor
(production 2005)**



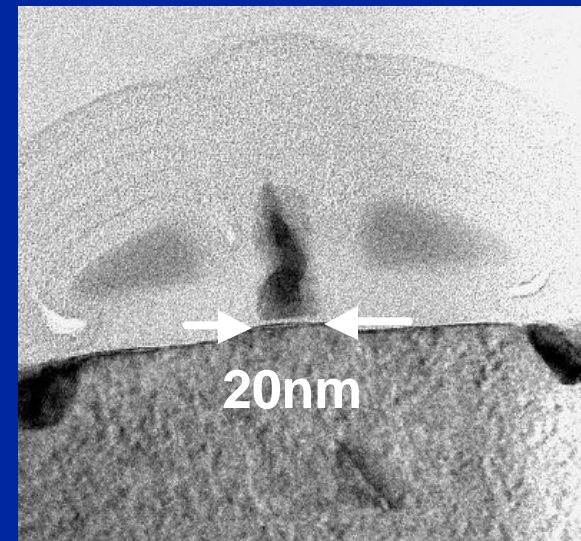
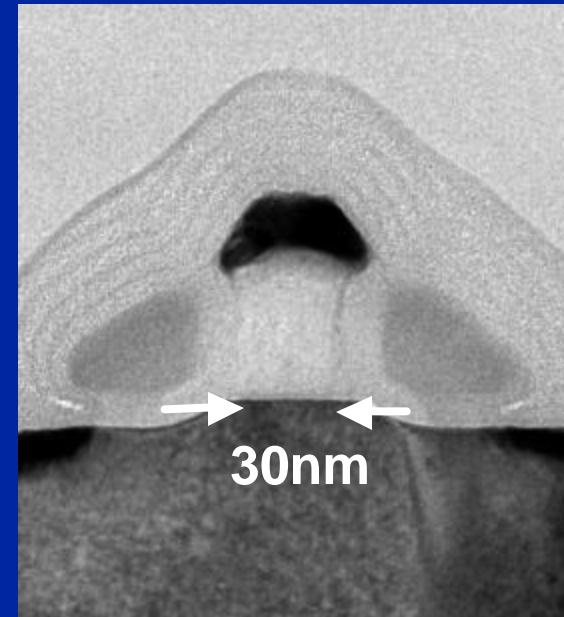
**20nm transistor
(research phase)**



Transistors as Small as DNA



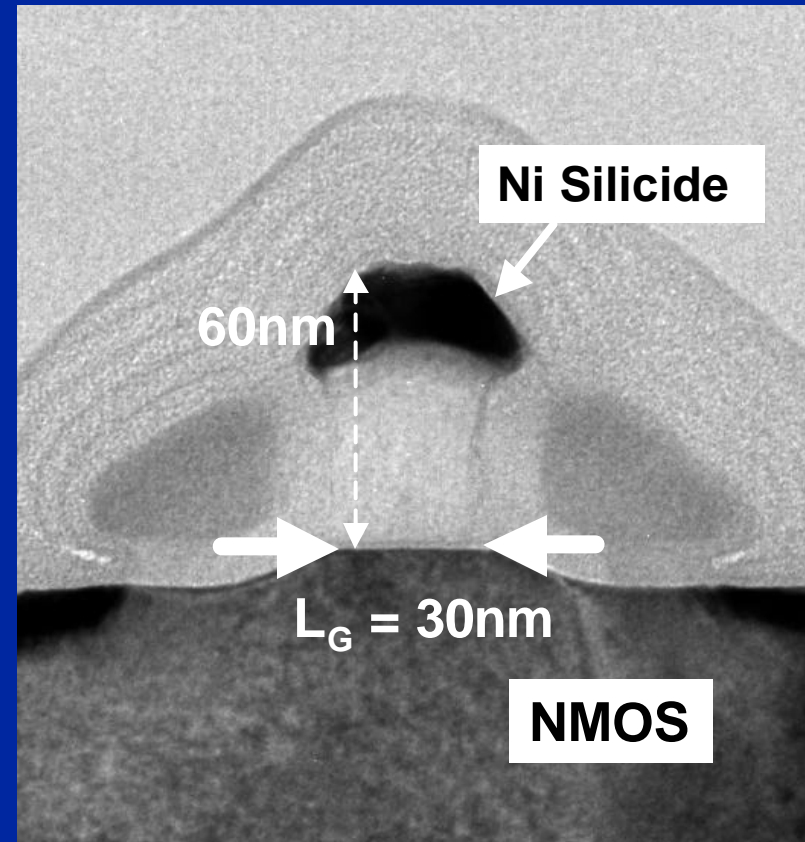
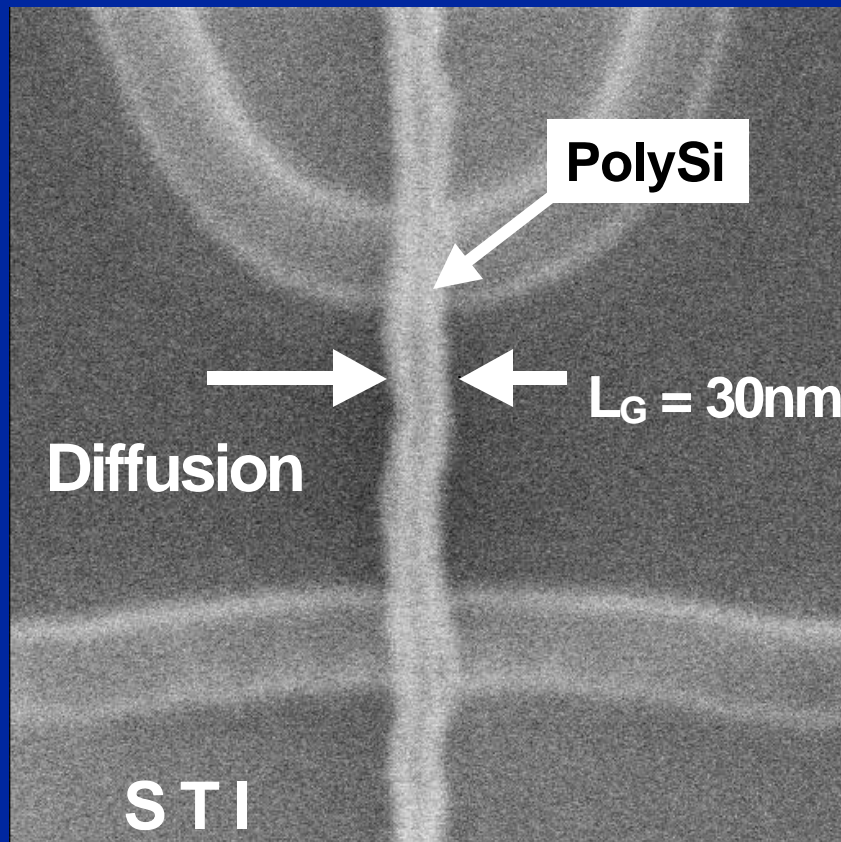
10nm Gold particle attached to Z-DNA
Antibody [John Jackson & Inman. Gene
1989 84 221-226]



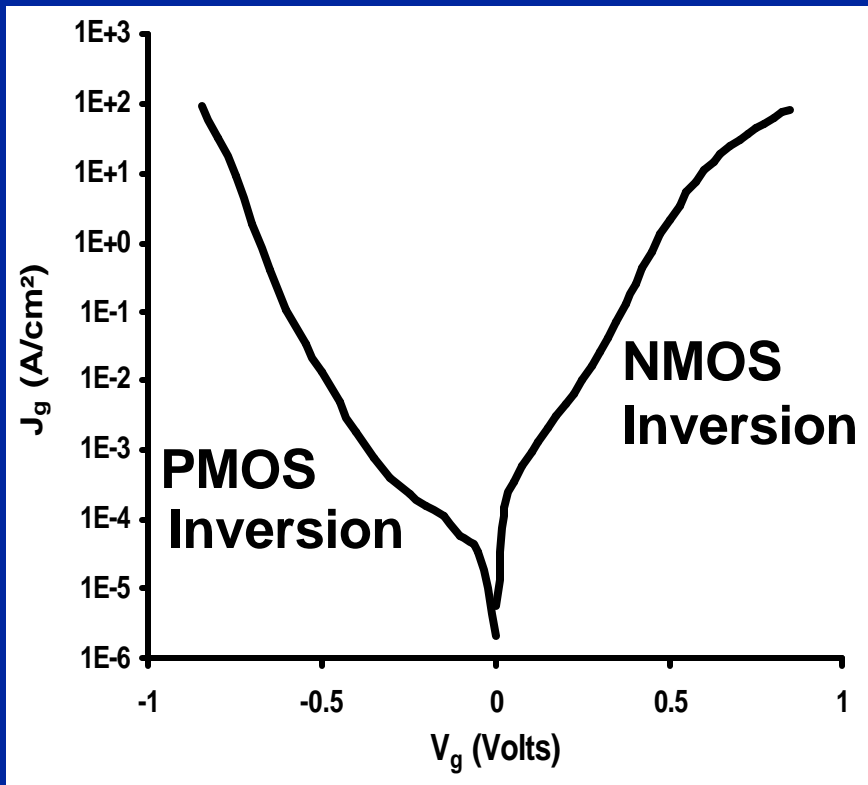
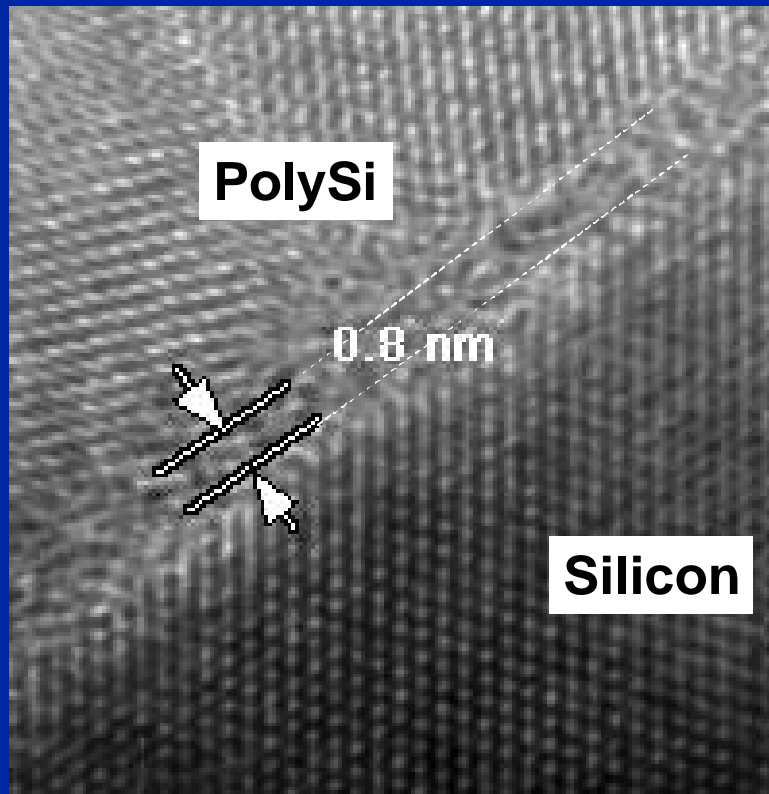
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30nm Physical Gate Length Transistor

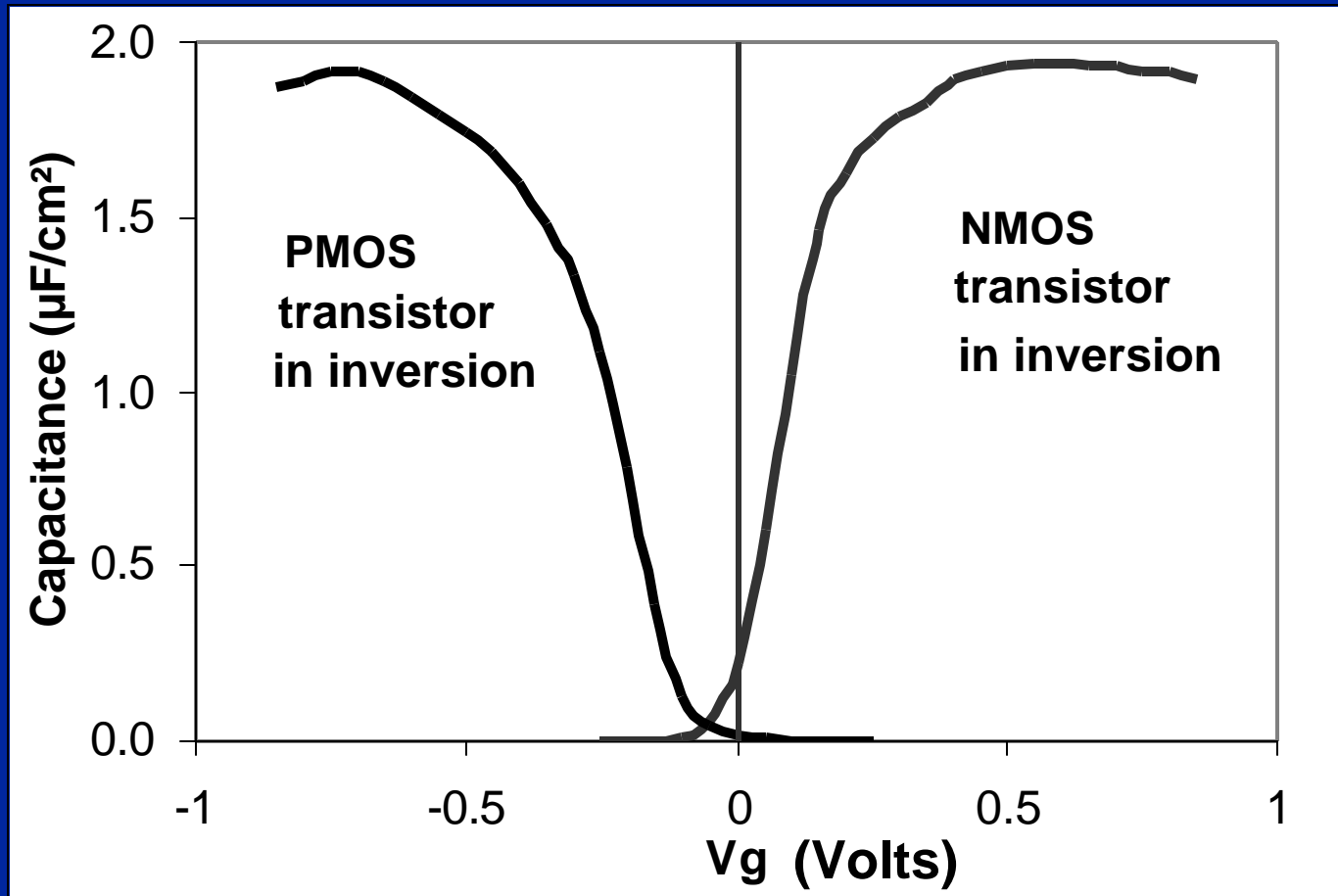


0.8nm Gate Oxide

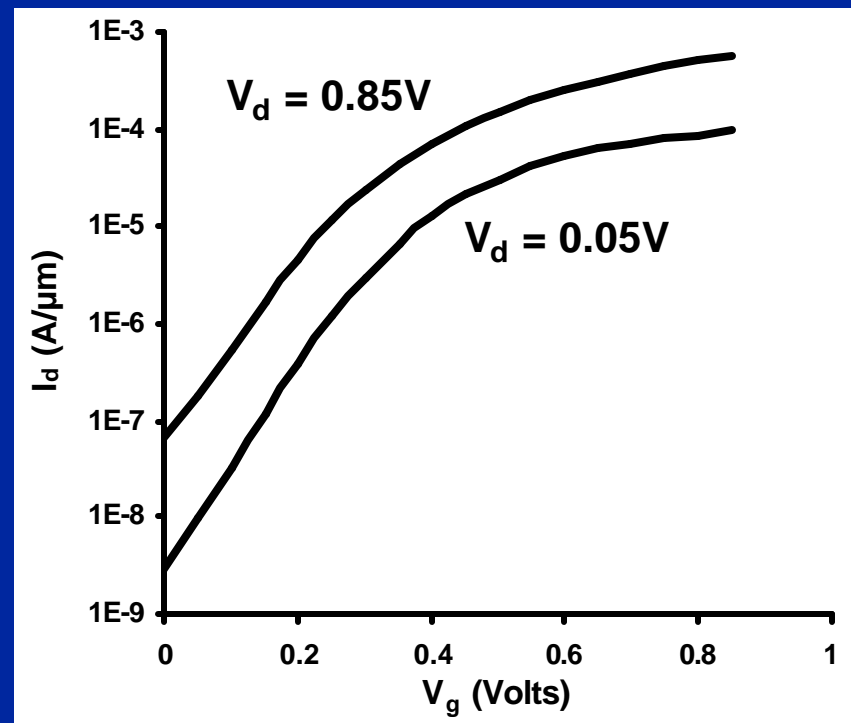
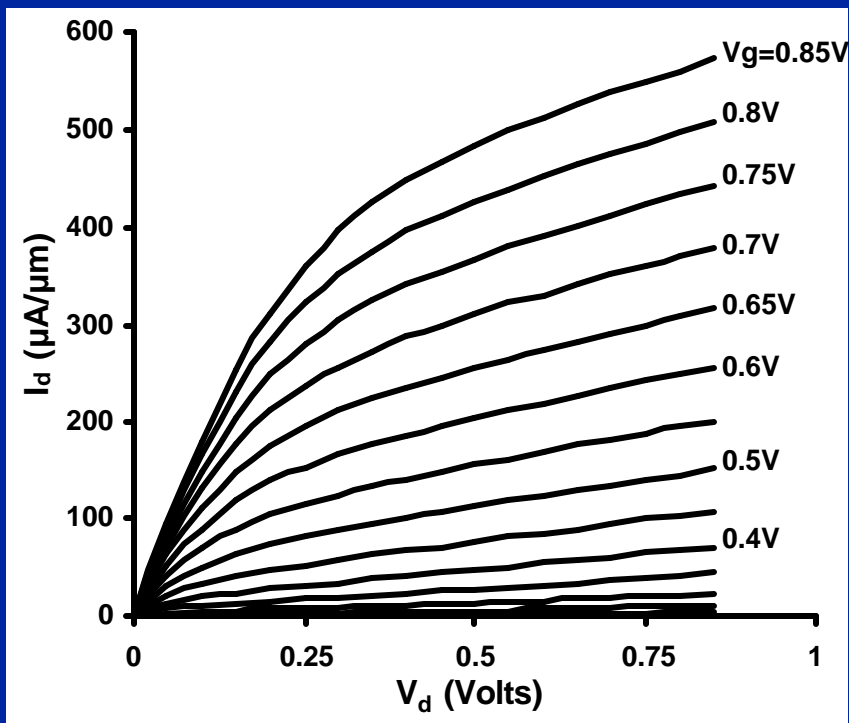


- 0.8nm gate oxide
- Gate oxide leakage ~25nA/um for 30nm L_g NMOS and PMOS at 0.85V inversion (room temperature)

Transistor Gate Inversion Capacitance for 0.8nm Gate Oxide

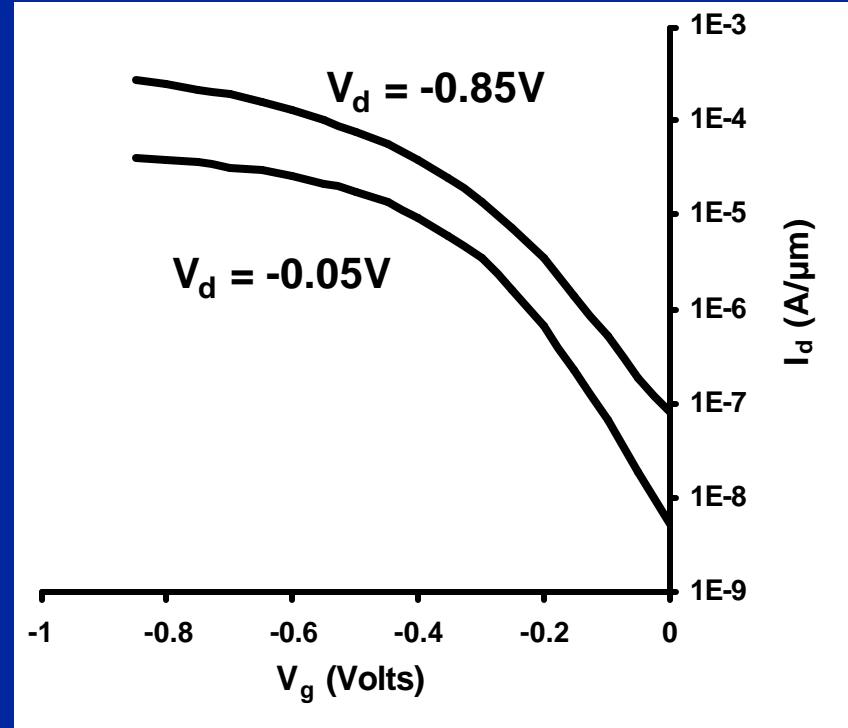
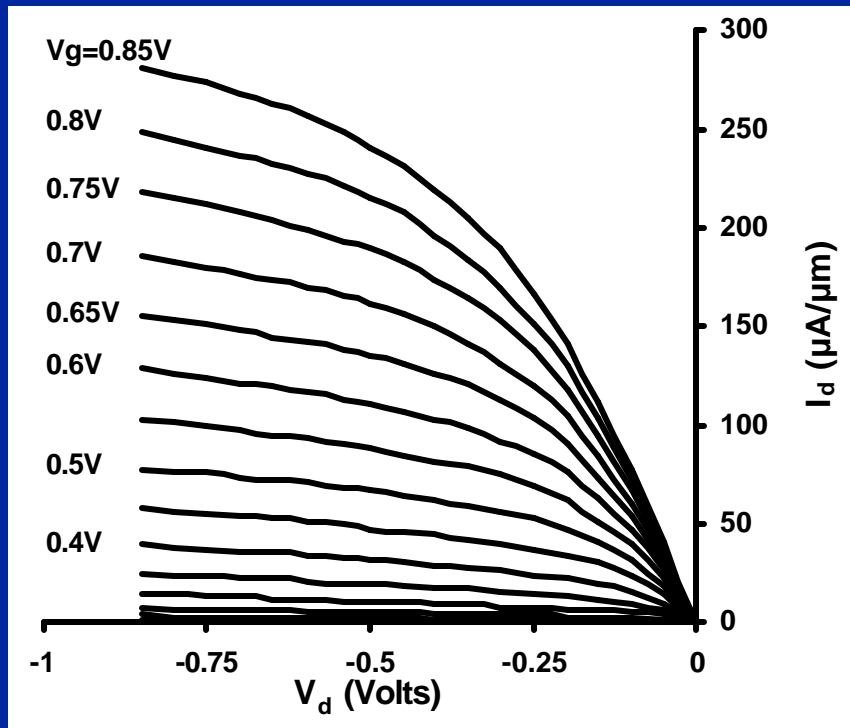


30nm L_G NMOS Transistor



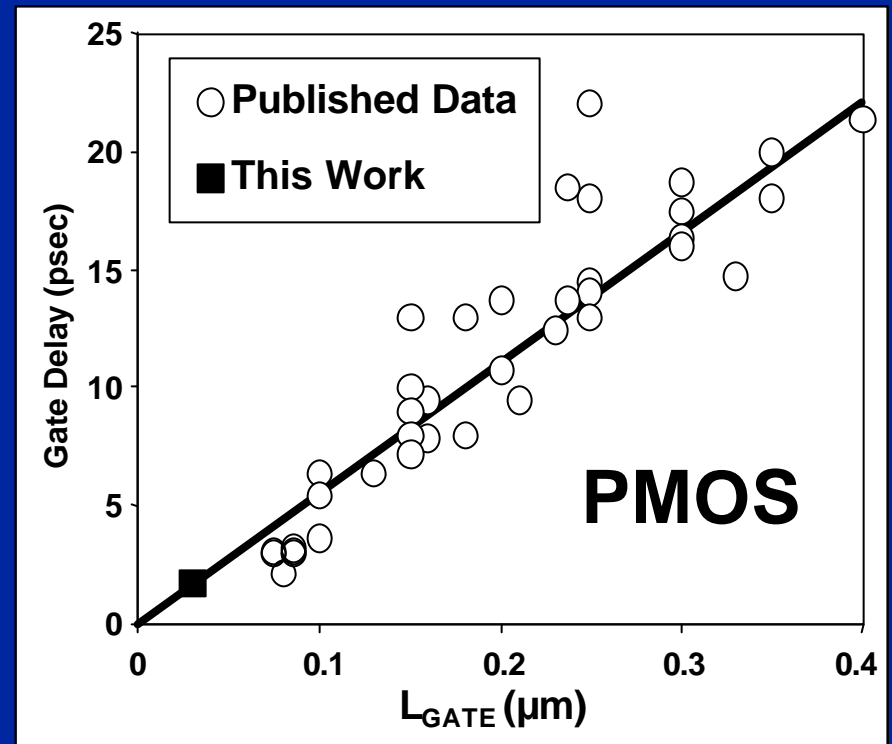
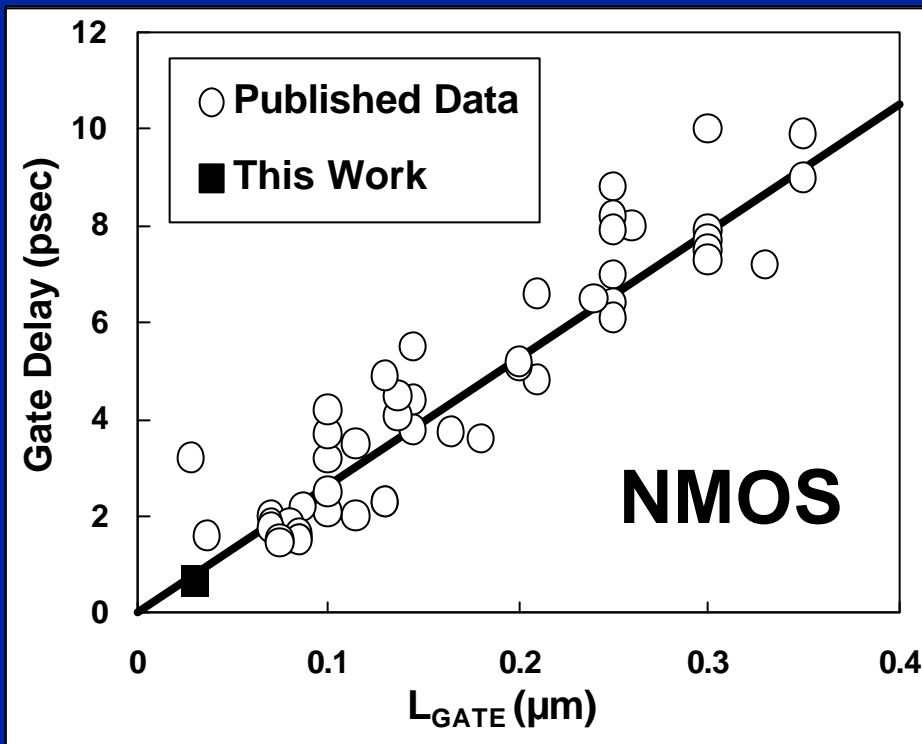
- $I_{on} = 0.57\text{mA}/\text{mm}$, $I_{off} = 60\text{nA}/\text{mm}$ at $V_{DD} = 0.85\text{V}$
- Subthreshold slope = $100\text{mV}/\text{decade}$
- DIBL = $125\text{mV}/\text{V}$

30nm L_G PMOS Transistor



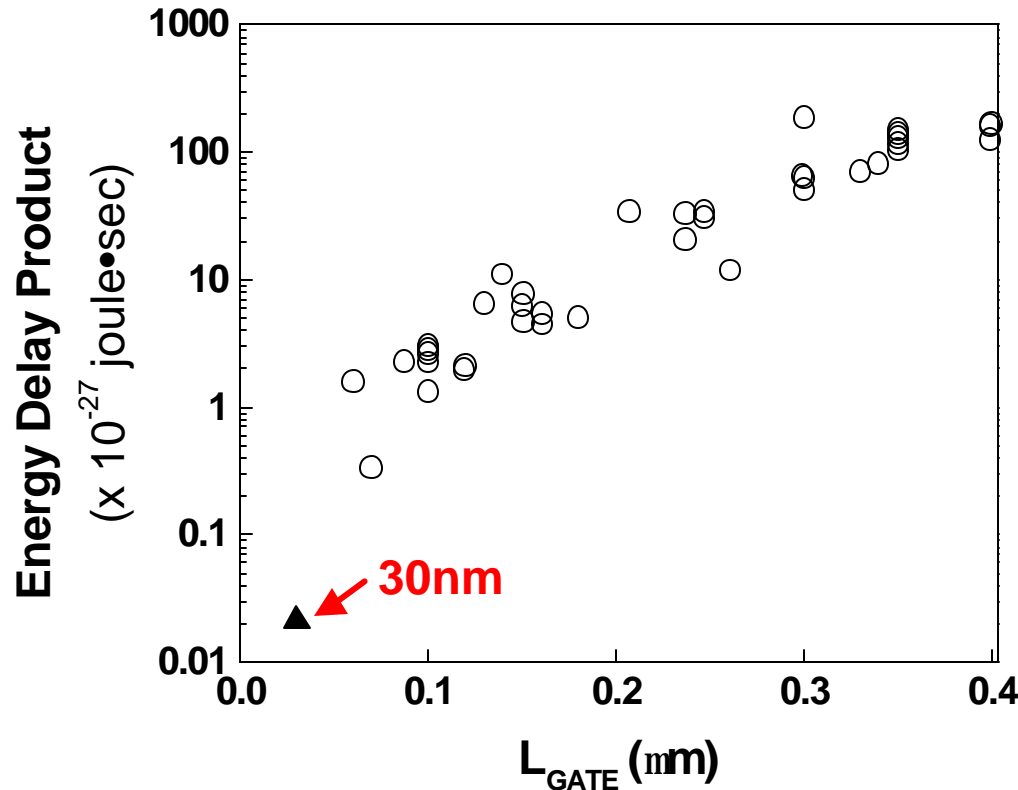
- $I_{on} = 0.28mA/mm$, $I_{off} = 80nA/mm$ at $V_{DD} = 0.85V$
- Subthreshold slope = 100mV/decade
- DIBL = 125mV/V

30nm Transistor CV/I Gate Delays



- NMOS gate delay = 0.85ps, PMOS gate delay = 1.7ps
- Gate delays continue to follow historical trends

NMOS Energy Delay Product ($CV^2 \times CV/I$) ----- Power and Speed

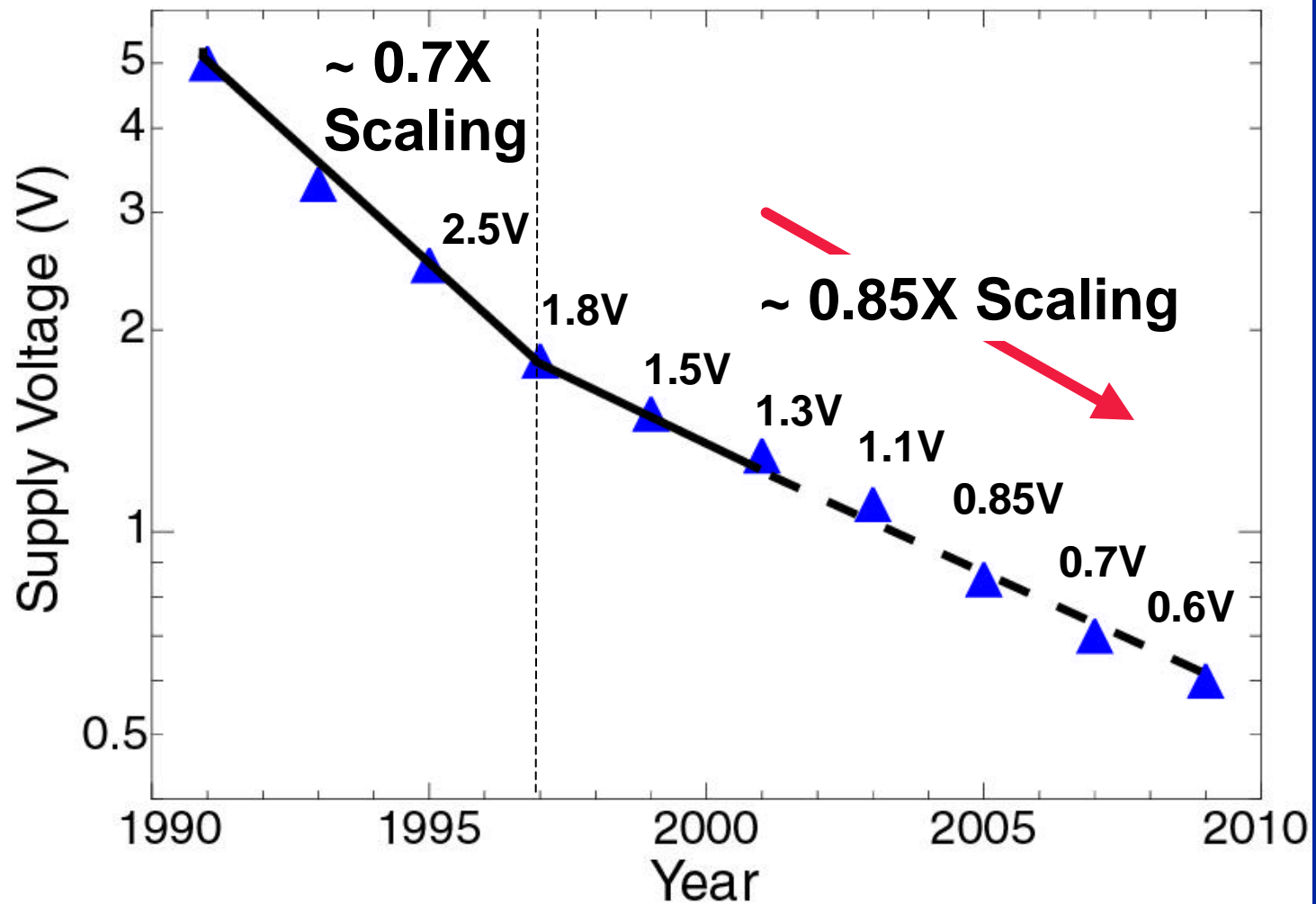


- Energy delay product reduces due to supply voltage and physical gate length scaling

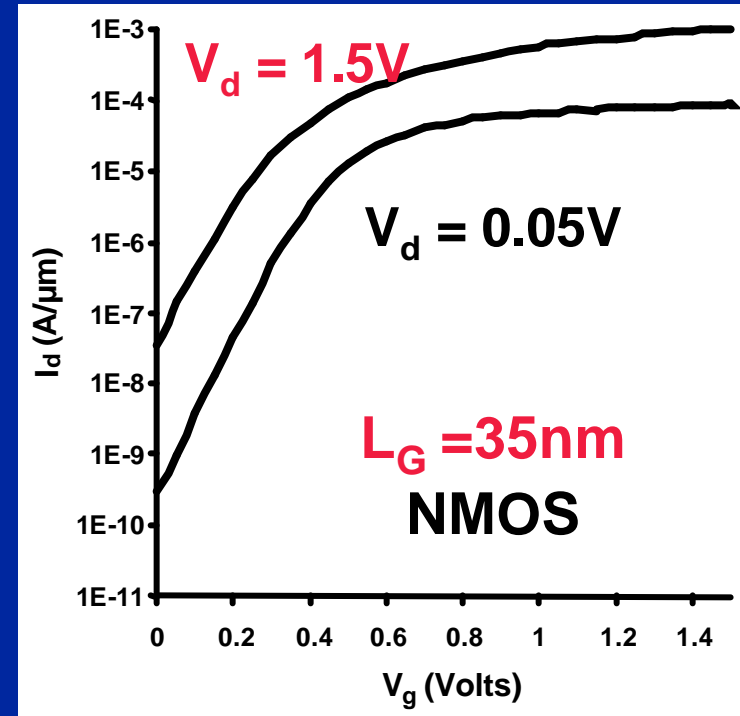
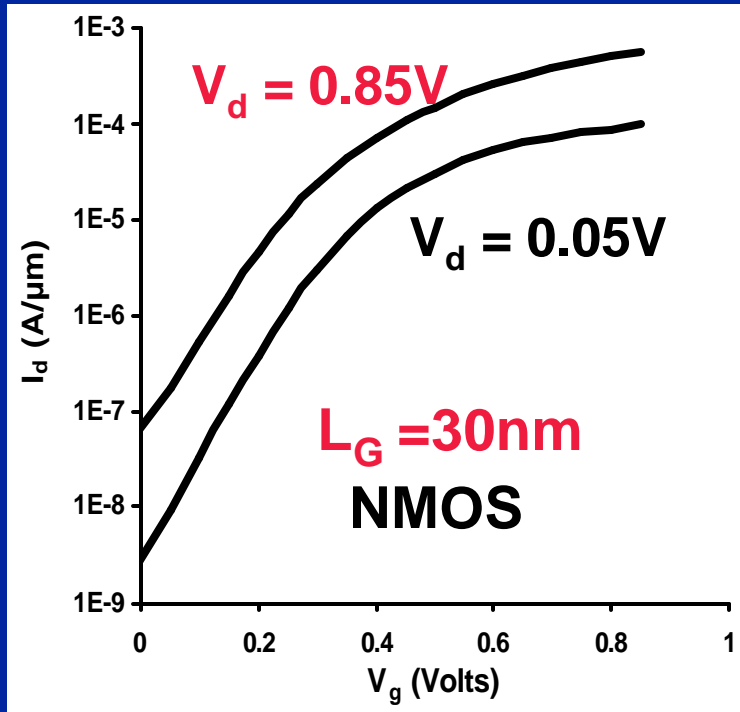
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Supply Voltage Scaling Trend

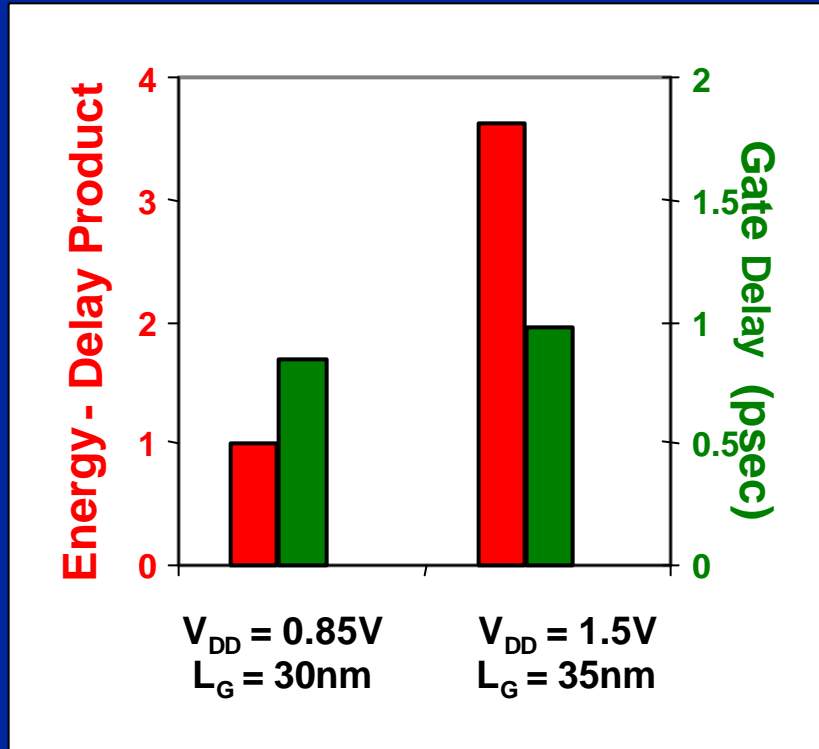


30nm L_G @ 0.85V Versus 35nm L_G @ 1.5V



- 35nm NMOS at $V_{DD} = 1.5\text{V}$
 - $I_{on} = 1.1\text{mA/mm}$, $I_{off} = 50\text{nA/mm}$, gate delay = 0.90ps
- 30nm NMOS at $V_{DD} = 0.85\text{V}$
 - $I_{on} = 0.57\text{mA/mm}$, $I_{off} = 60\text{nA/mm}$, gate delay = 0.85ps

Importance of Low V_{DD} : Energy-Delay Product



Energy-Delay Product:
 $CV^2 \times CV/I = C^2V^3/I$

- 35nm NMOS @ 1.5V has >3.5X higher energy-delay product than 30nm NMOS @ 0.85V
- The choice of low V_{DD} (<1.0V) is important for the 65nm technology node and beyond

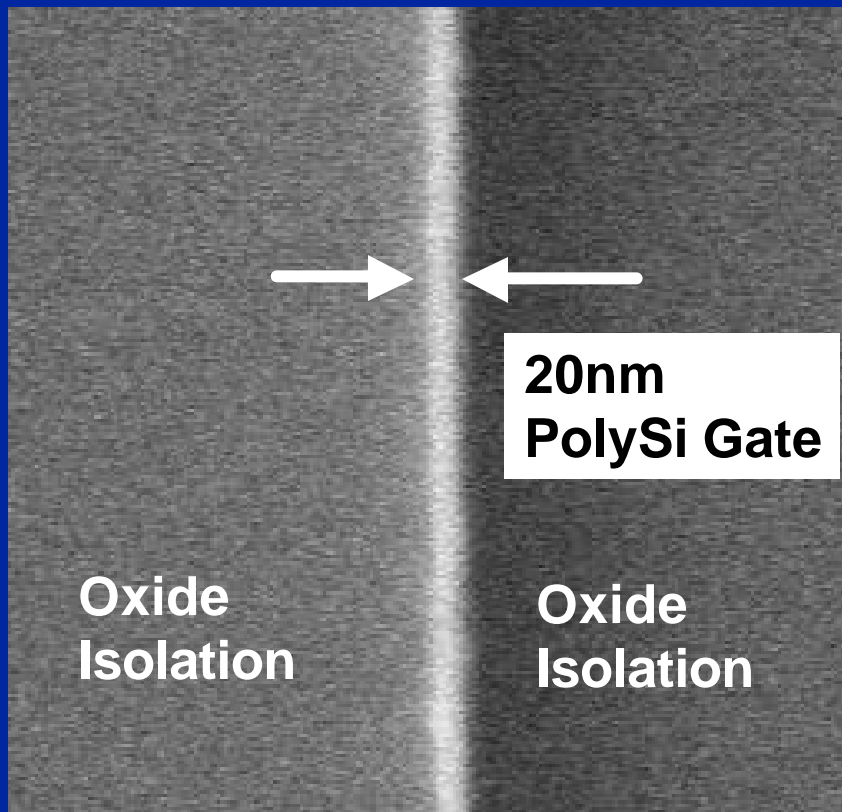
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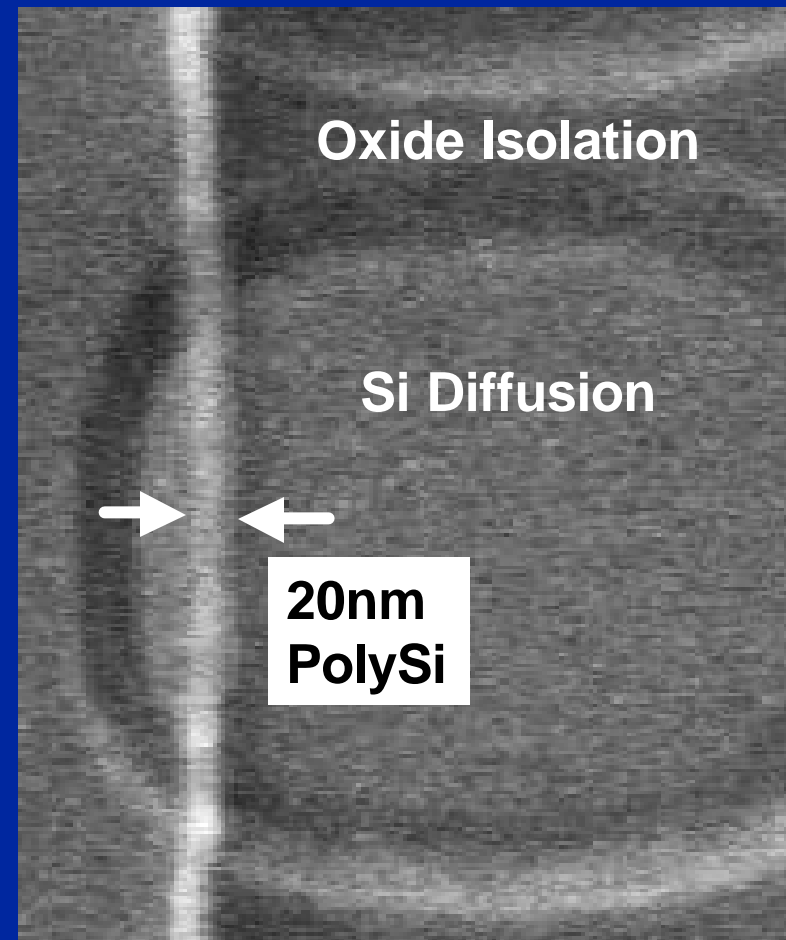
20nm Transistor Research

- **45nm technology node in production 2007**
 - Transistor physical gate length ~20nm
 - Transistor research for 45nm logic technology node in progress
- **20nm planar CMOS transistors one of the many research topics**
 - 20nm planar CMOS transistors fundamentally feasible? **(YES)**
 - Gate oxide thickness approaching zero for T_{ox} scaling beyond 0.8nm
 - Alternative gate stack

20nm Physical PolySi Gate

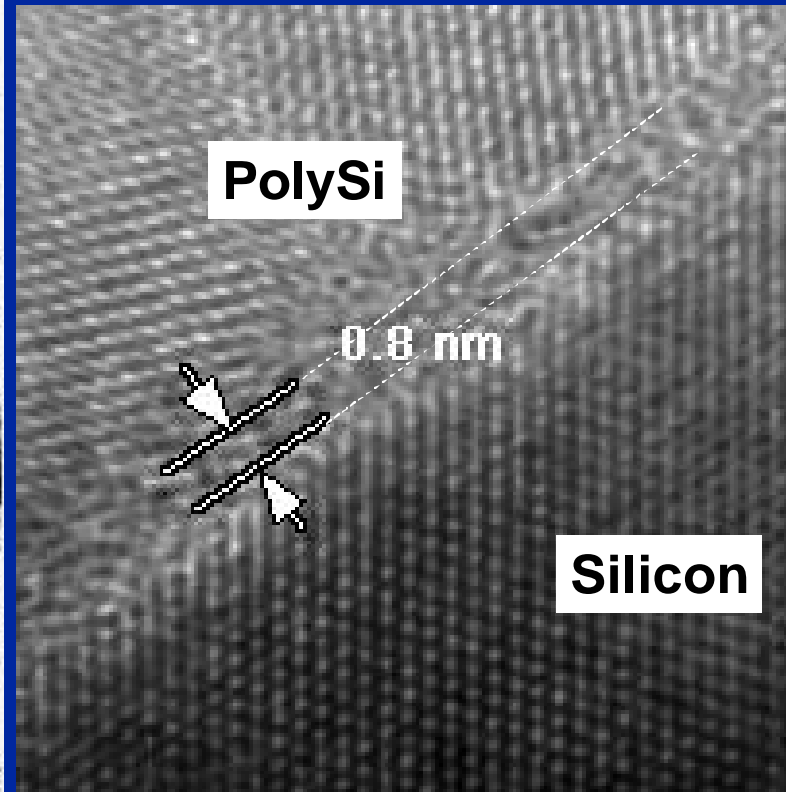
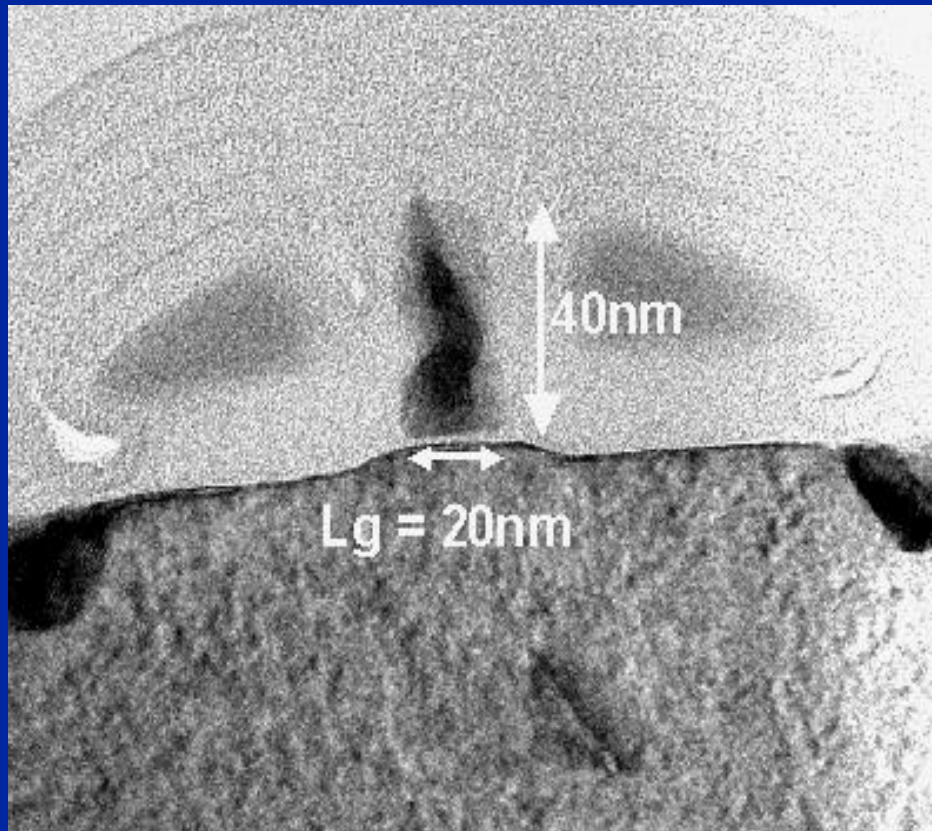


20nm polySi gate on oxide isolation



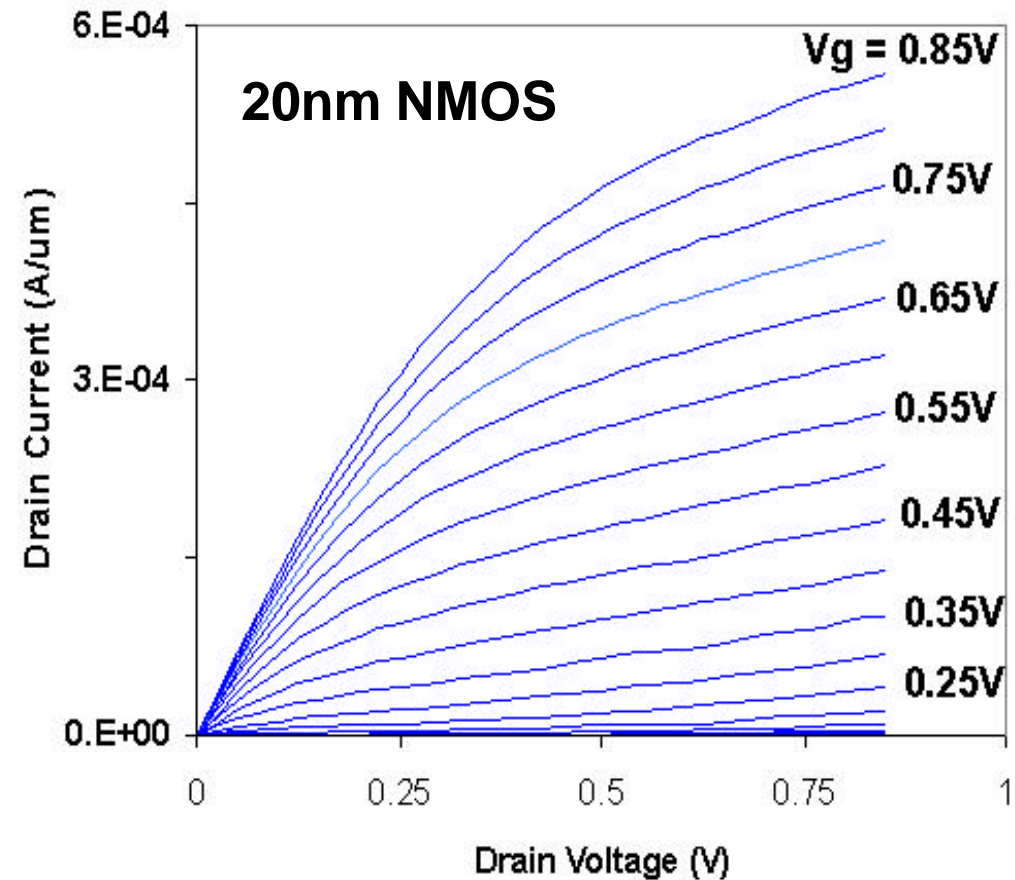
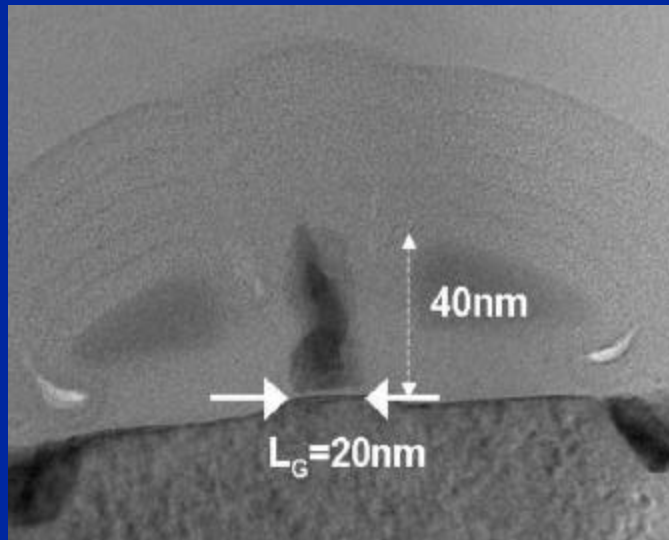
20nm polySi gate on oxide isolation and Si diffusion

20nm Physical Gate Length NMOS Transistor

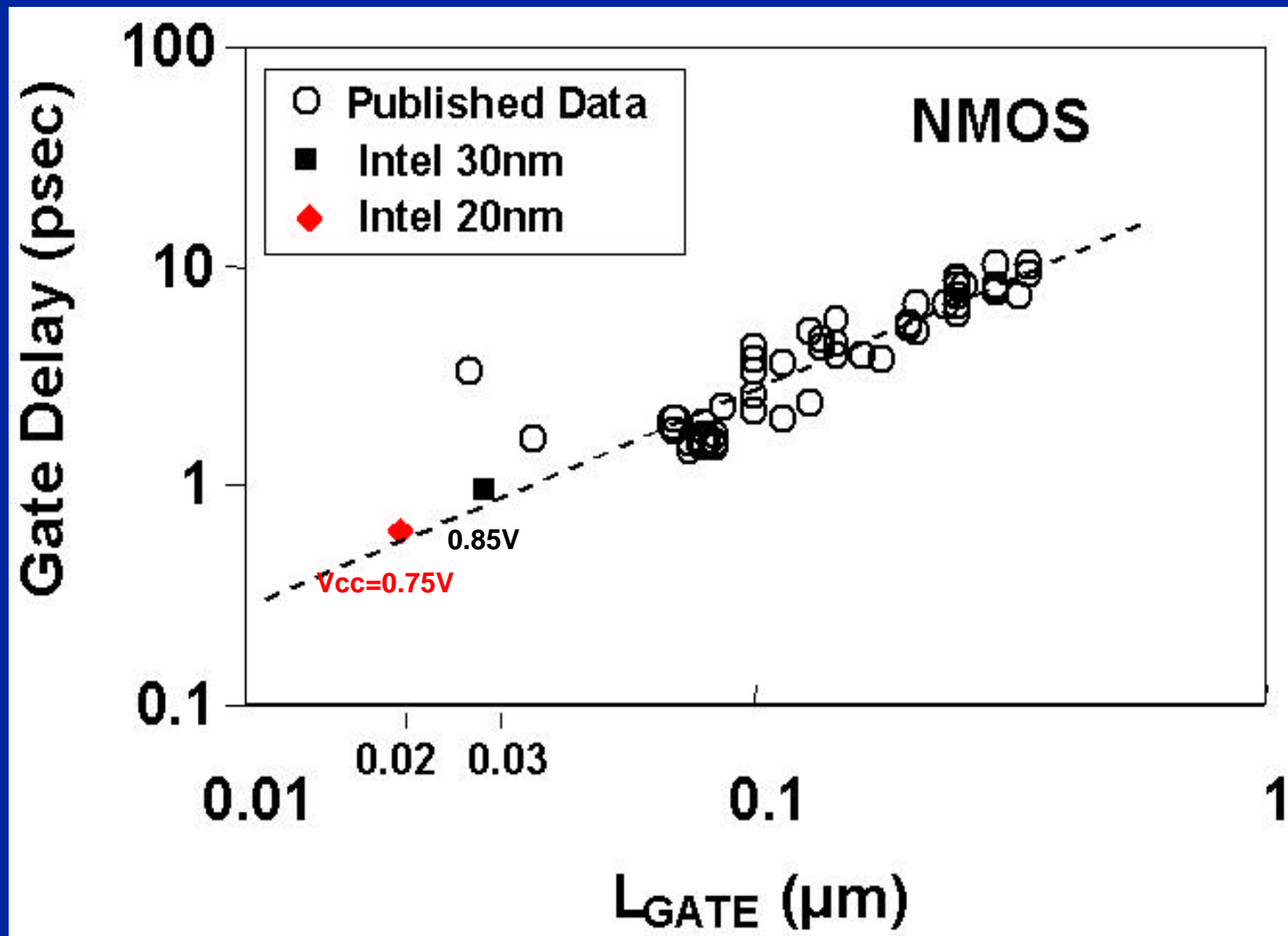


- 0.8nm conventional gate oxide

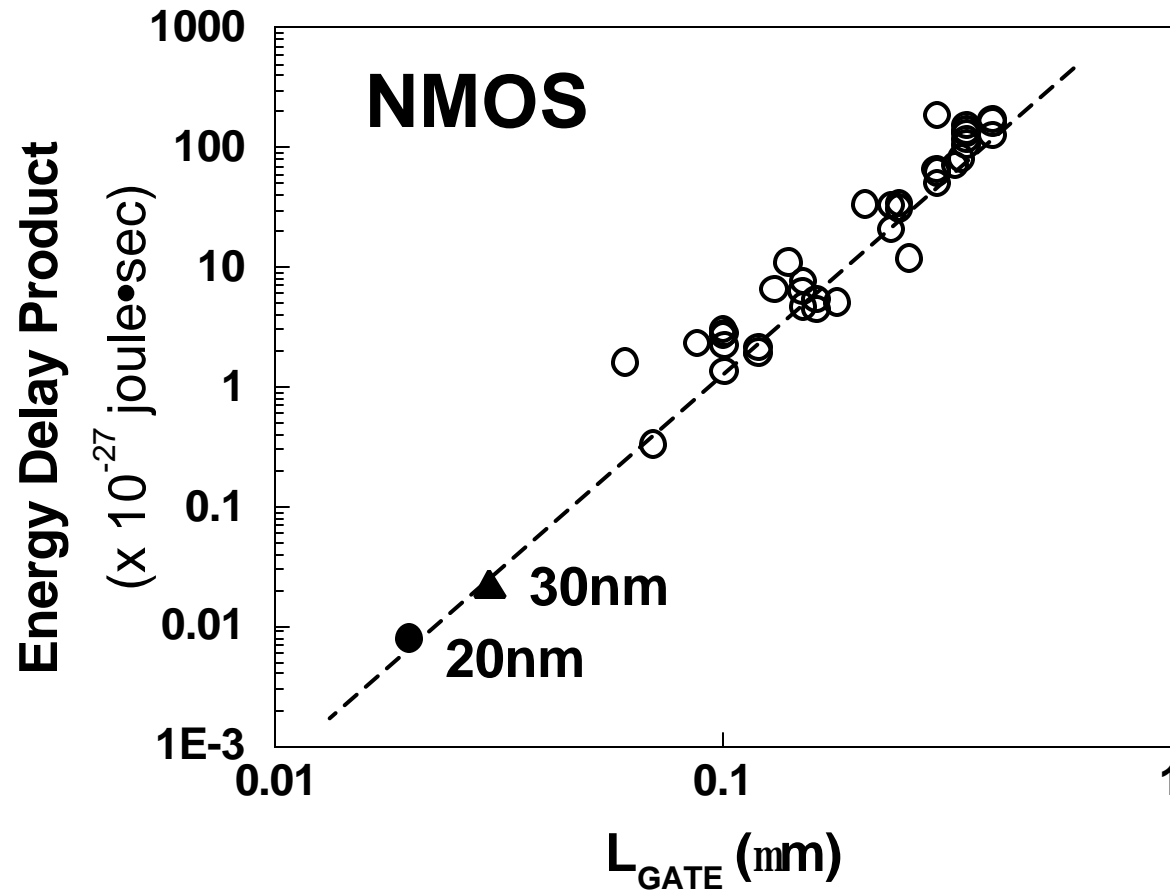
20nm Physical Gate Length NMOS Transistor



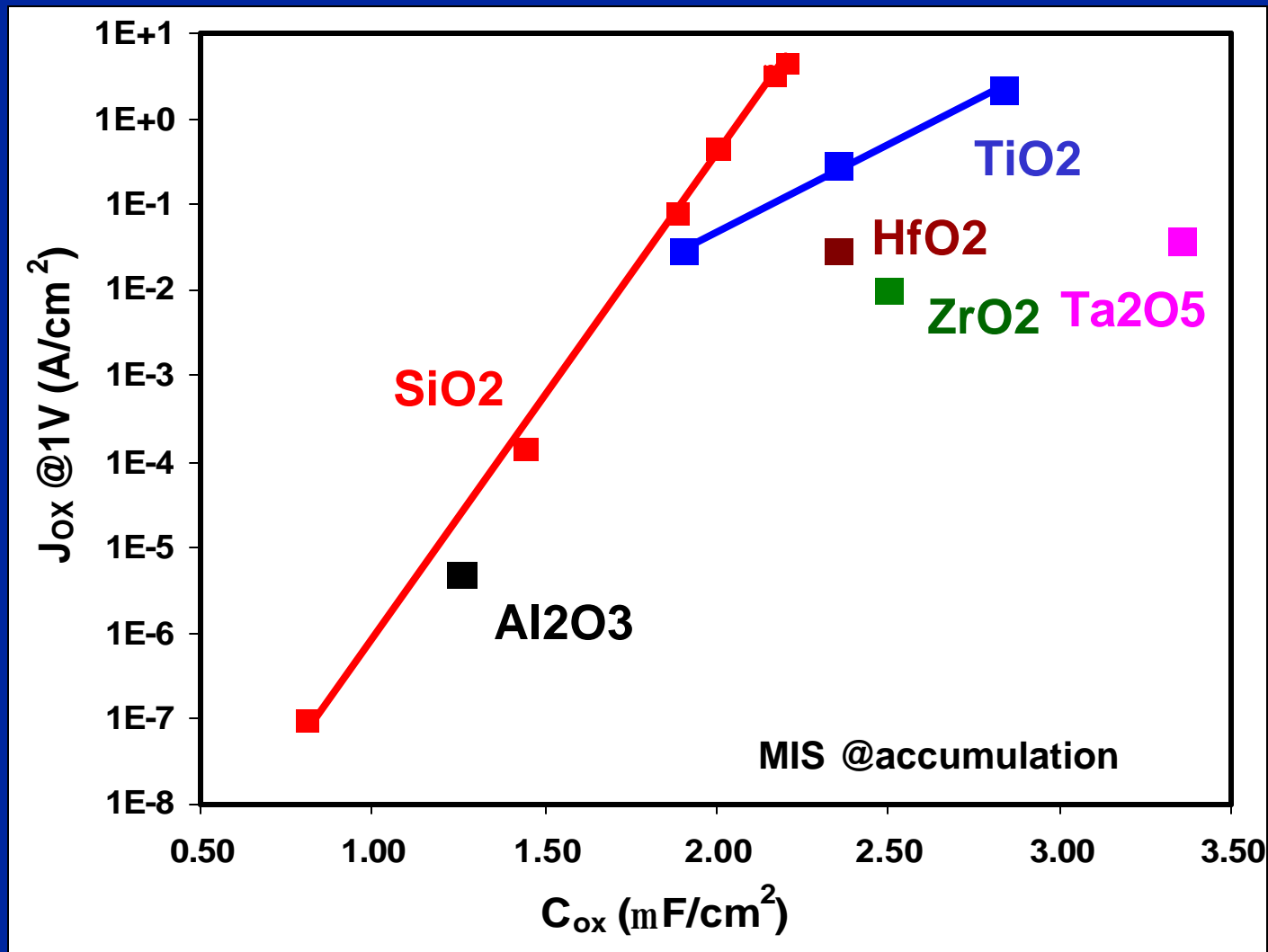
Gate Delay Trend Continues



Energy Delay Product Trend Continues



Alternative Gate Dielectrics



Summary

- High-performance 30nm physical gate length CMOS transistors have been demonstrated for the 65nm technology node, which will be ready for production 2005
- Research on 20nm physical gate length transistor and related topics are being conducted for the 45nm technology node